

Application No.: 09/671,567

Docket No.: JCLA5635

In the Specification:

Please amend the second paragraph on page 4 as follow:

Fig. 1 schematically shows a block diagram for carrying out the method of the present invention. The circuit of defective pixel address detection for an image sensor comprises at least a memory element 10 and an address comparator 20. The memory element 10 is used for storing the defective pixel addresses which are detected during the image sensor is tested. The memory element 10 can be a fuse array, for example. The address comparator 20 receives a current sensor address of the image sensor ~~Sensor_addr~~Sensor_addr and fetches a defective pixel address Def_pixel_addr from the memory element 10. The address comparator 20 then compares the two addresses, ~~Sensor_addr~~Sensor_addr and Def_pixel_addr. If the two addresses ~~Sensor_addr~~Sensor_addr and Def_pixel_addr are the same, which means a hit, the address comparator 20 generates a flag bit F to indicate that the current sensor address of the image sensor is a defective pixel. The index of the memory element 10 is increased by one unit, such as 1, to begin another cycle of address comparison. If the two addresses ~~Sensor_addr~~Sensor_addr and Def_pixel_addr are not the same, which means a miss, the address comparator 20 sets the flag bit F to a value, such as 0, to indicate that the current sensor address of the image sensor is a good pixel. And then another cycle of address comparison is begun.